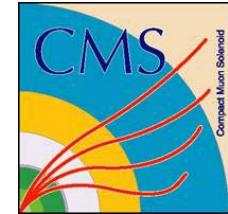




CMS ECAL

LECC 2004 – Boston, USA



Qualification of the Front End Cards for the CMS ECAL



Project Team:

E. Corrin:

M Gastal:

M. Hansen:

P. Petit:

Software design

Digital design

Project supervision

PCB design

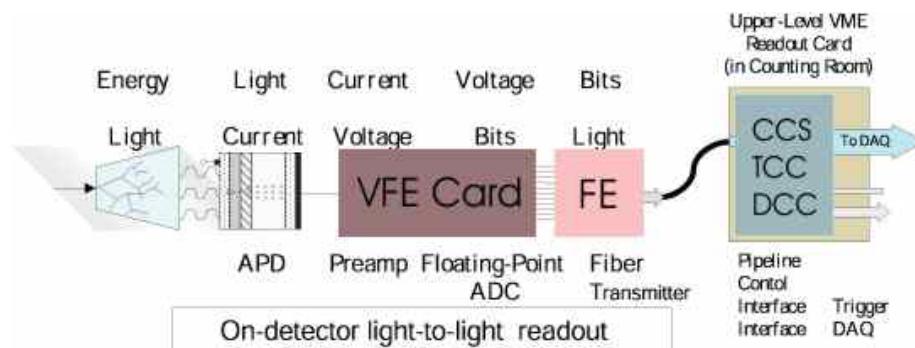


Introduction

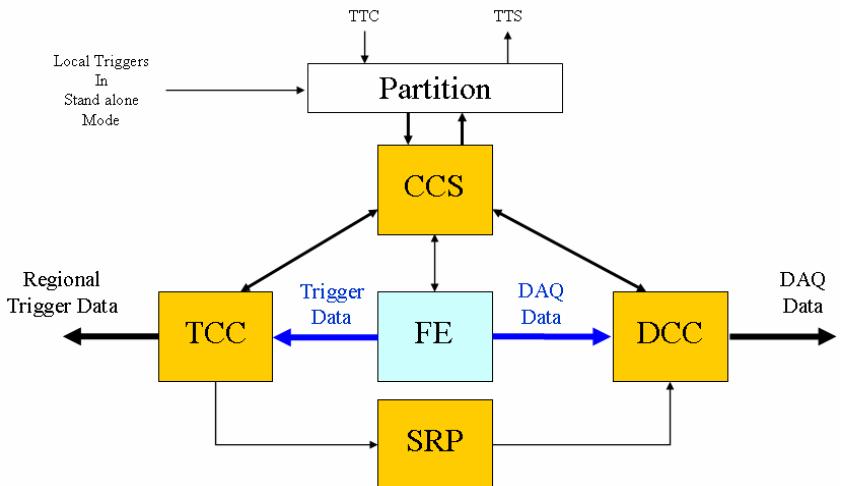


CMS ECAL trigger and data acquisition system changed in 2002

- ⇒ Same functionality
- ⇒ Readout and trigger primitives generation

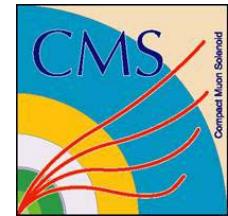


CCS: Clock and Control System
TCC: Trigger Concentrator Card
DCC: Data Concentrator Card



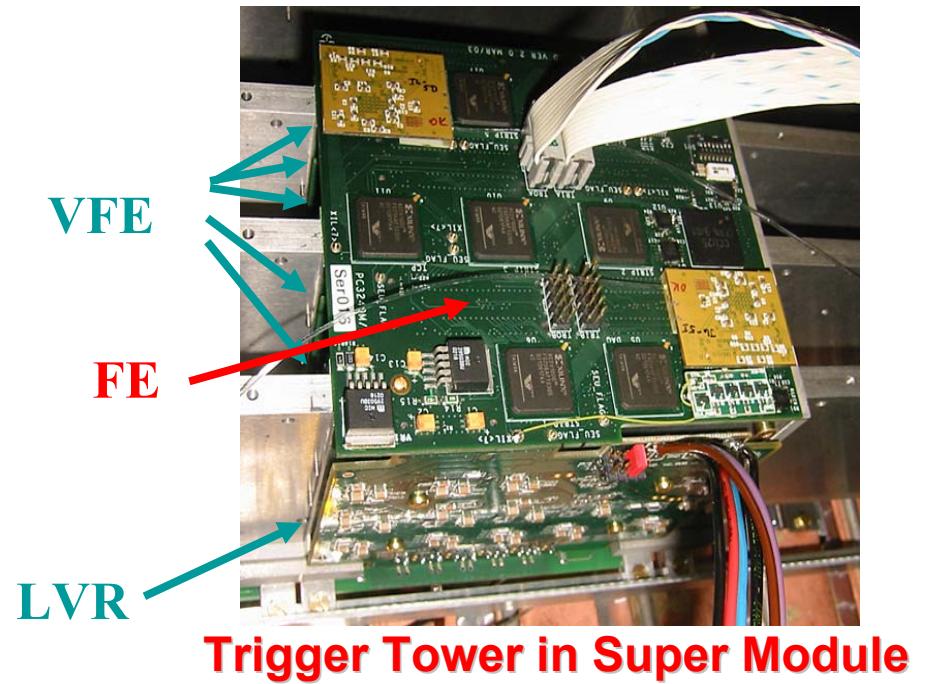
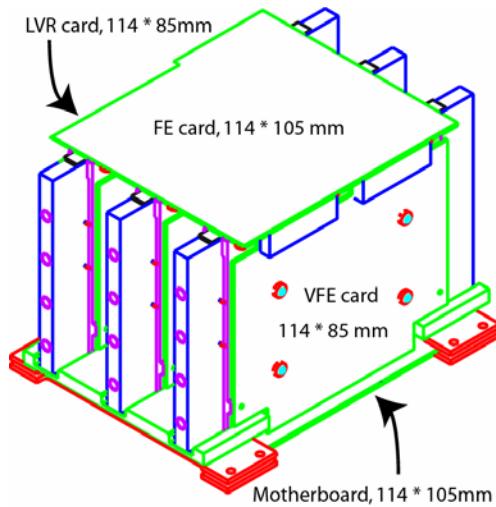


Introduction



New electronics modules

- ⇒ VFE, FE, LVR...
- ⇒ Focus on FE card



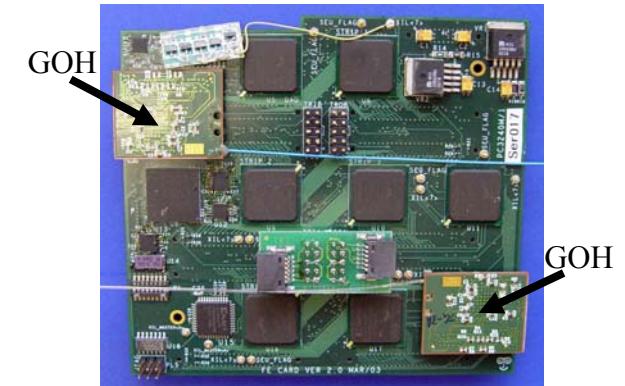
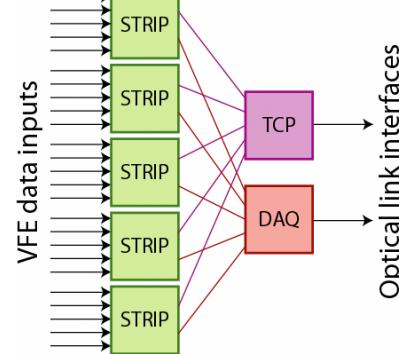
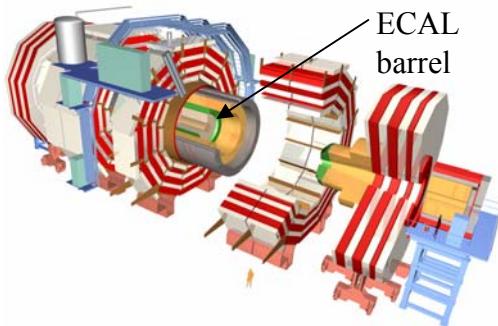


Introduction

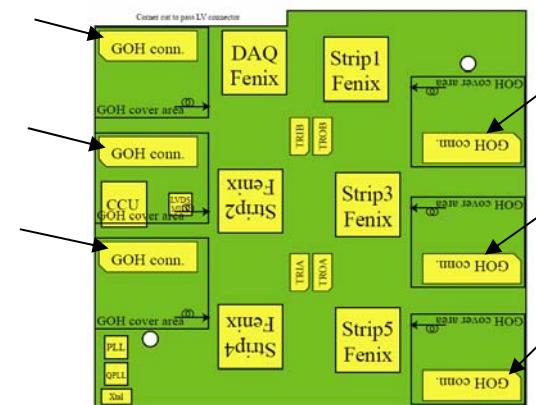
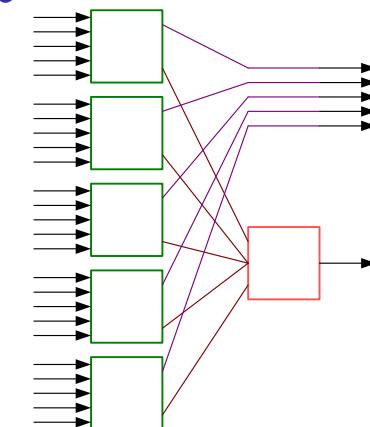
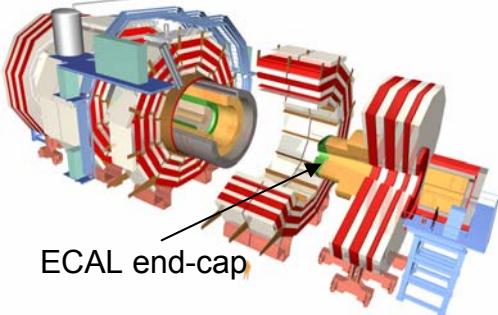


2 models of FE Cards

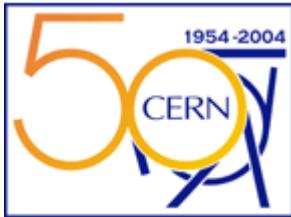
⇒ Fe card for barrel



⇒ Fe card for End Cap



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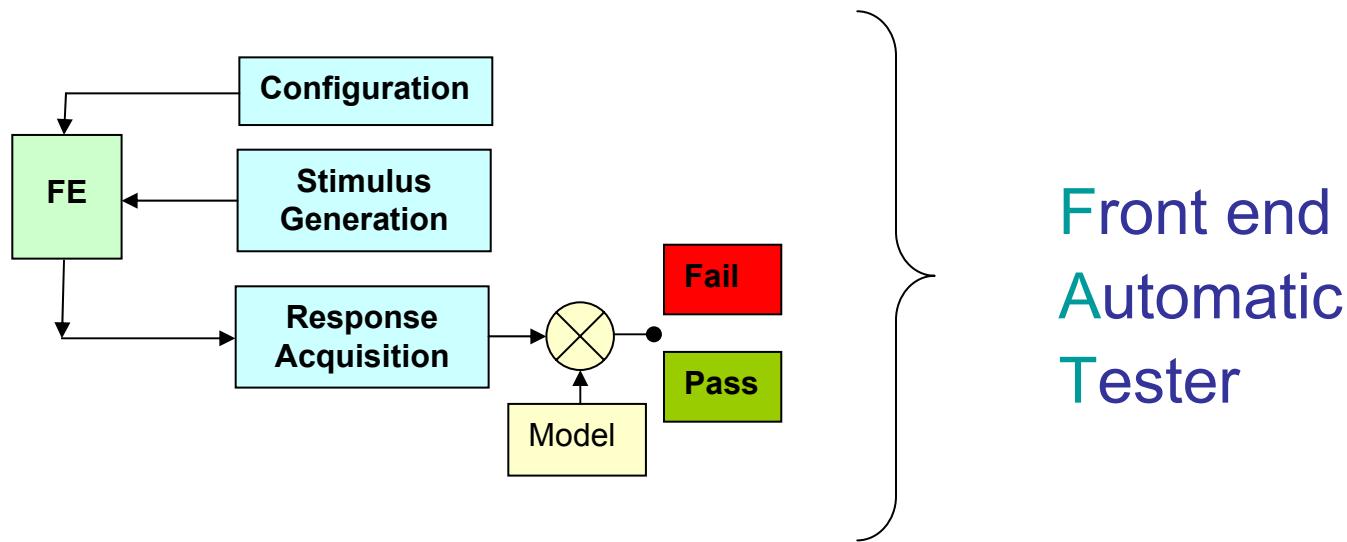


Introduction



Focus: FE Cards

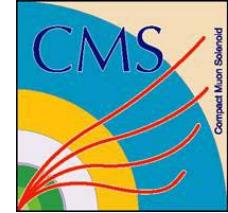
- ⇒ 4,000 cards to be produced
- ⇒ Need for a qualification system



Beyond a test system, a valuable simulation tool...



Outline



General Description

- Hardware
- System Control
- On-board ICs

Data Flow

- Standard Operations

Design Details

- Digital Design
- Typical Test
- Simulation Tool

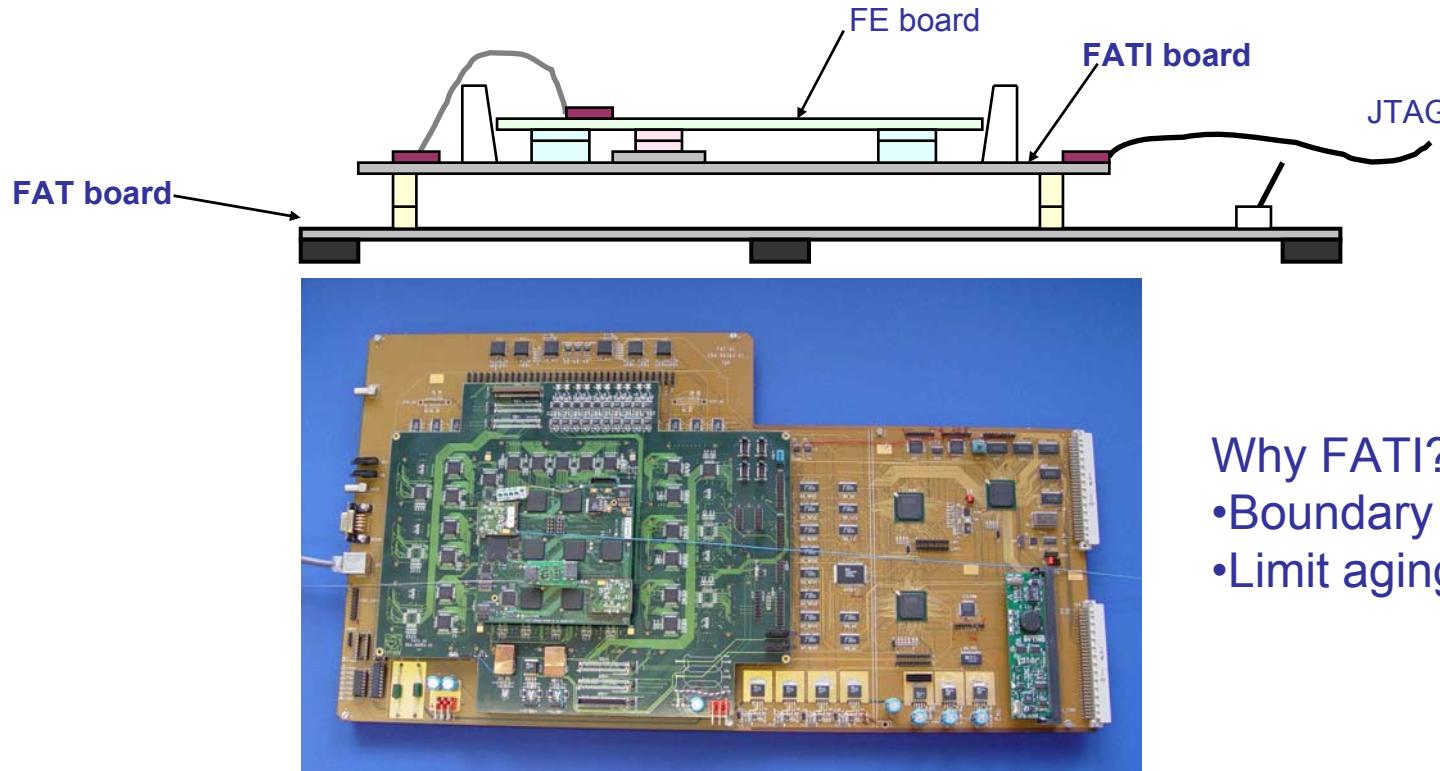


Hardware



New cards:

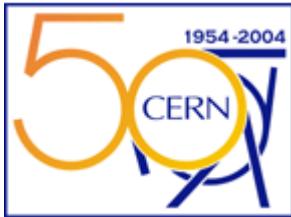
- ⇒ FAT card: 300mm × 550mm 12 Layers → 4 units
- ⇒ FATI card: 300mm × 250mm 6 Layers → 15 units



Why FATI?

- Boundary scan implemented
- Limit aging of FAT

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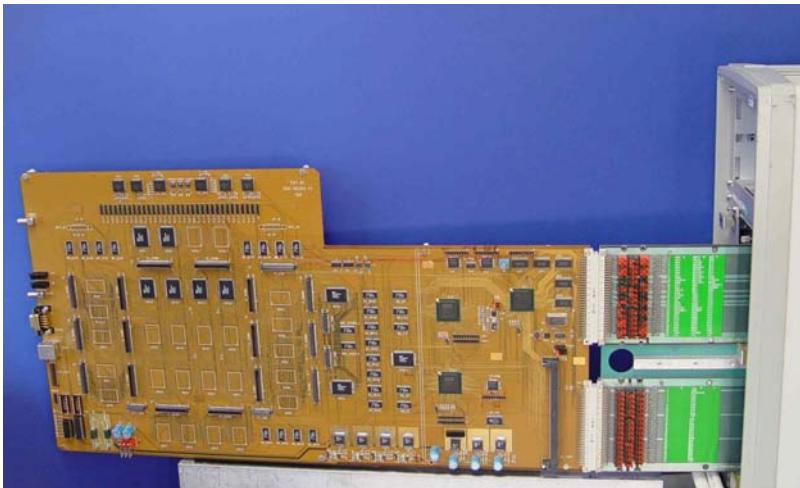
System Control



VME

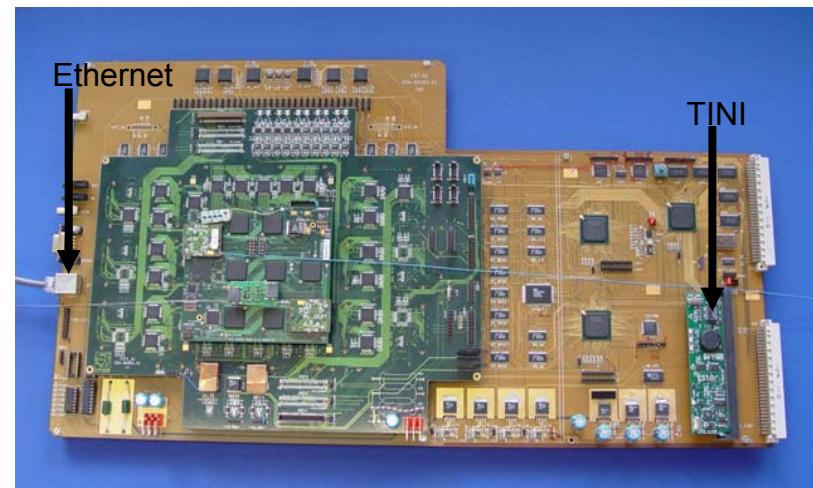
vs.

TINI



For debugging purposes:

- +Rack and rack controller available
- +Widely used environment
- Handling difficult
- Space consuming

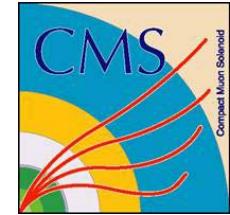


For production tests:

- +Ethernet controlled
- +Easier handling
- +Compact set-up
- Limited memory resources



Dual Port Random Access Memories



33 16-bit×64k DPRAMs on board:

- 25 Data DPRAMs ⇒

To simulate 5 VFE cards of 5 16-bit channels each

- 7 REC DPRAMs ⇒

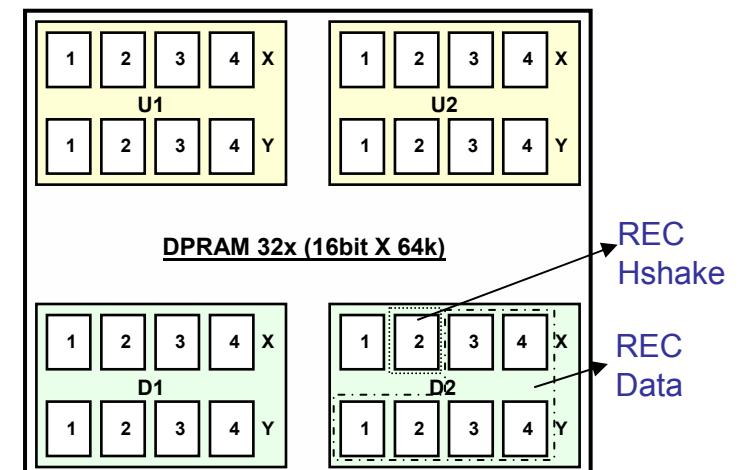
Record FE card response

From 6 17-bit optical links (end cap version)

16-bit data + 1 bit handshake

- 1 RT DPRAM ⇒

Generate a trigger



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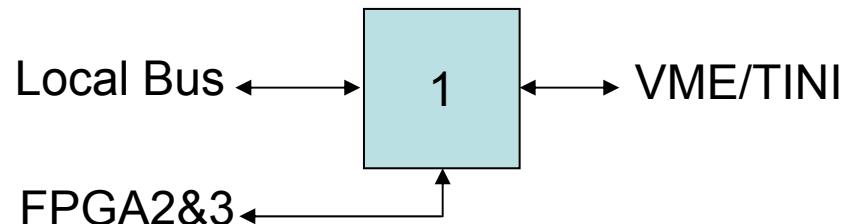


Programmable Logic

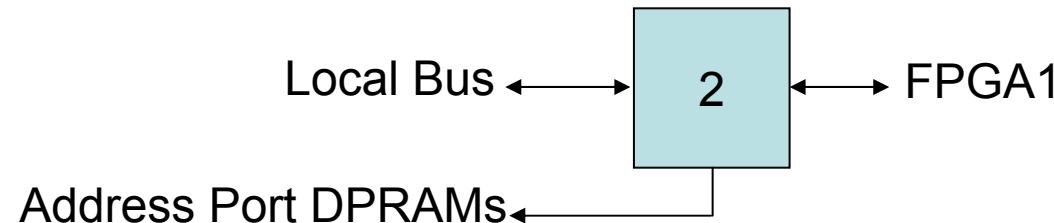


3 Xilinx xc2s200-6fg456 FPGAs on board:

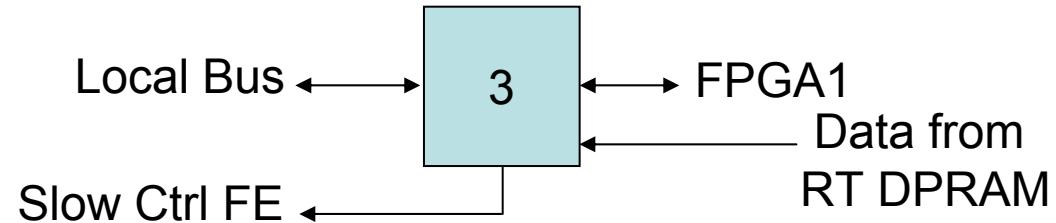
•FPGA1⇒



•FPGA2⇒

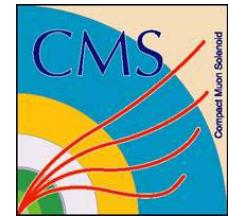


FPGA3⇒

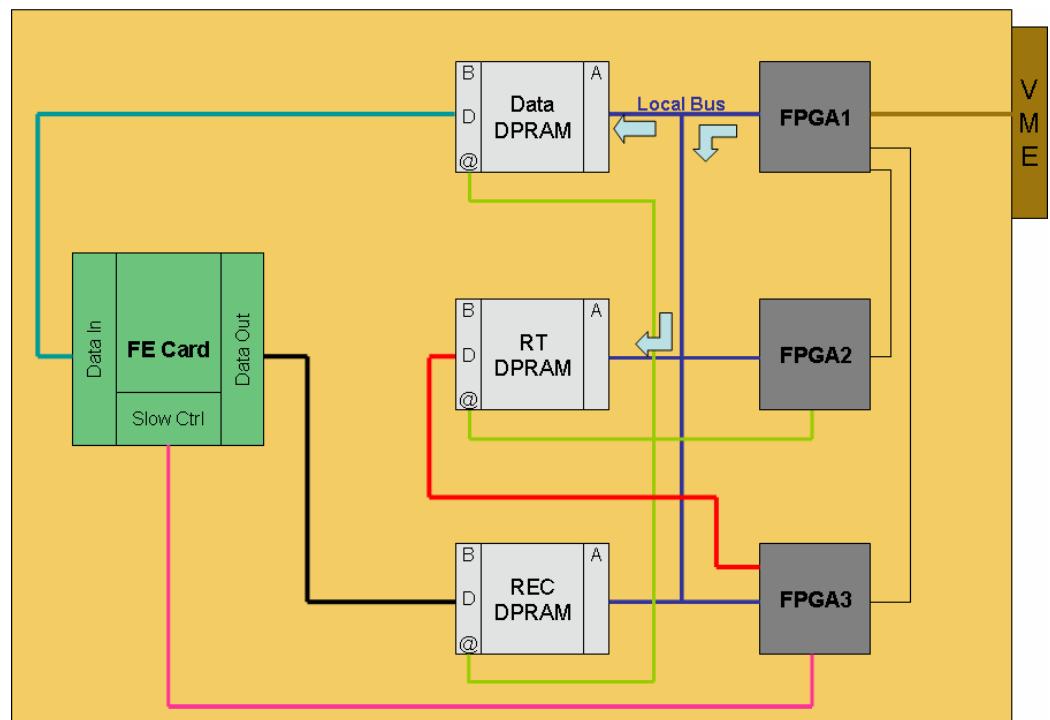




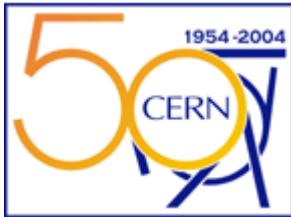
Data Flow (1)



Writing to, Reading from DPRAMs



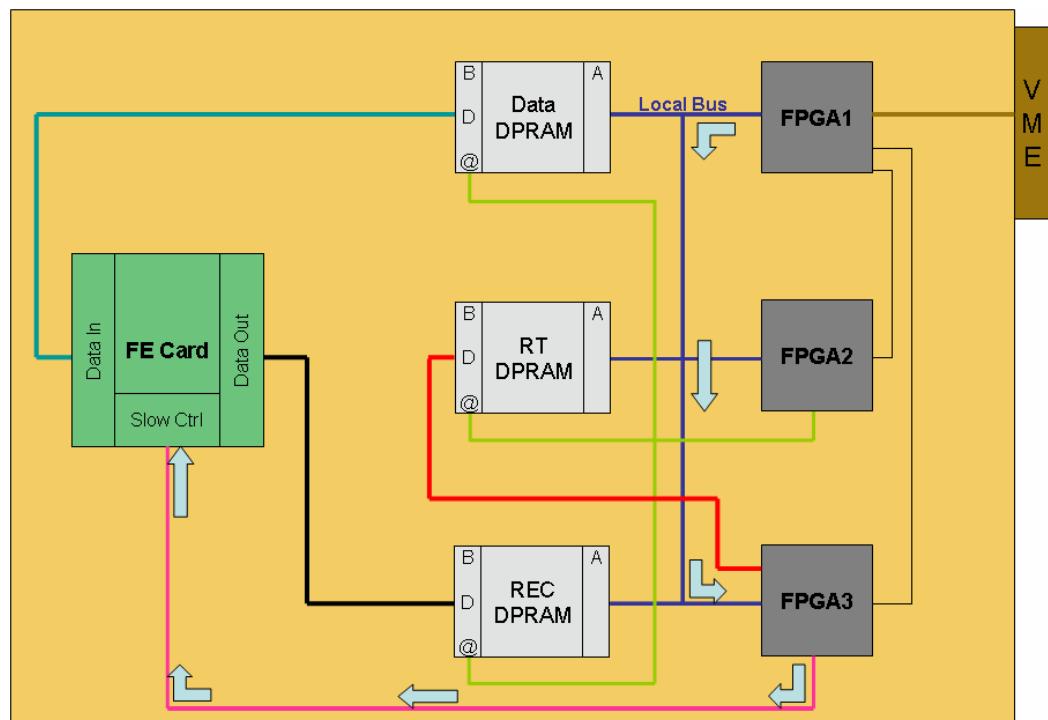
Software request
VME command
Decoding → FPGA1
Data broadcasting on local bus



Data Flow (2)



Configuration of the FE card



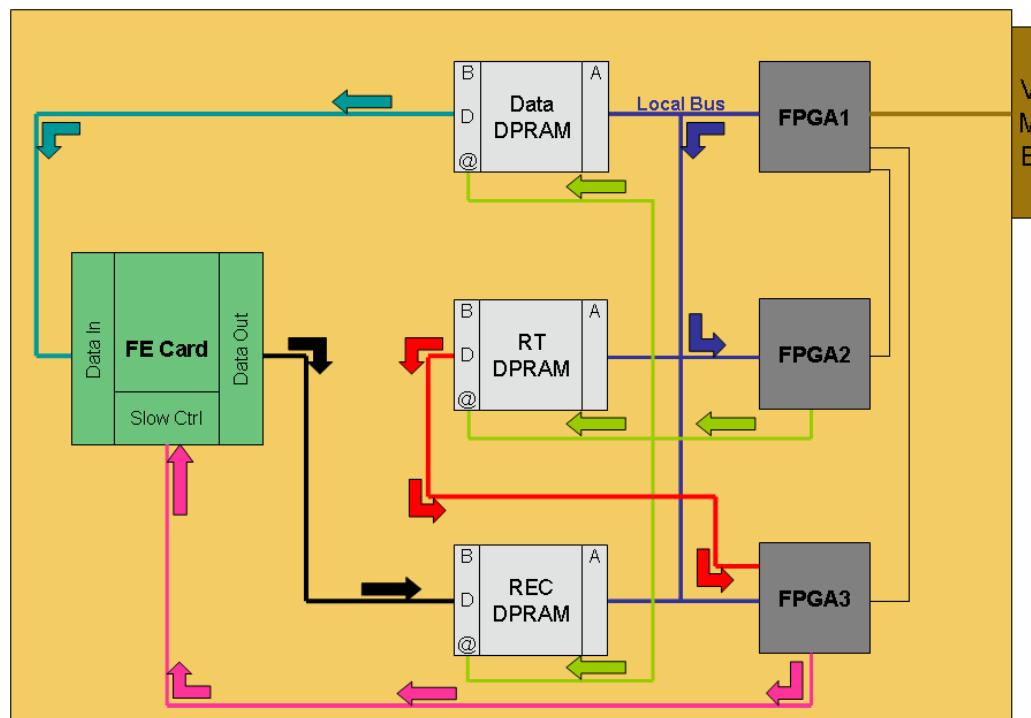
Software request
VME command
Decoding → FPGA1
Data broadcasting on local bus
Decoding → FPGA3
Token Ring Communication



Data Flow (3)



Stimulus sending

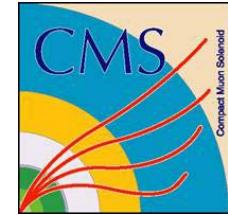


Software request
VME command
Decoding → FPGA1
Data broadcasting on local bus
Decoding → FPGA2
Data sending to FE
Data recording from FE
When trigger from RT DPRAM
L1 Missing pulse to FE

Read back response from FE
Comparison with model



Digital design



FPGA1: Board management

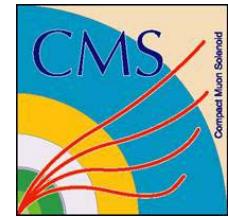
- VME & TINI interface
 - R/W operations
- FPGAs communication interface
 - Use of Local Bus + handshake signals
- Local bus management
 - Buffers management to avoid collision

FPGA2: Pattern Generation

- Load start address of stimulus
- Set length of broadcasting sequence
- Start broadcasting sequence

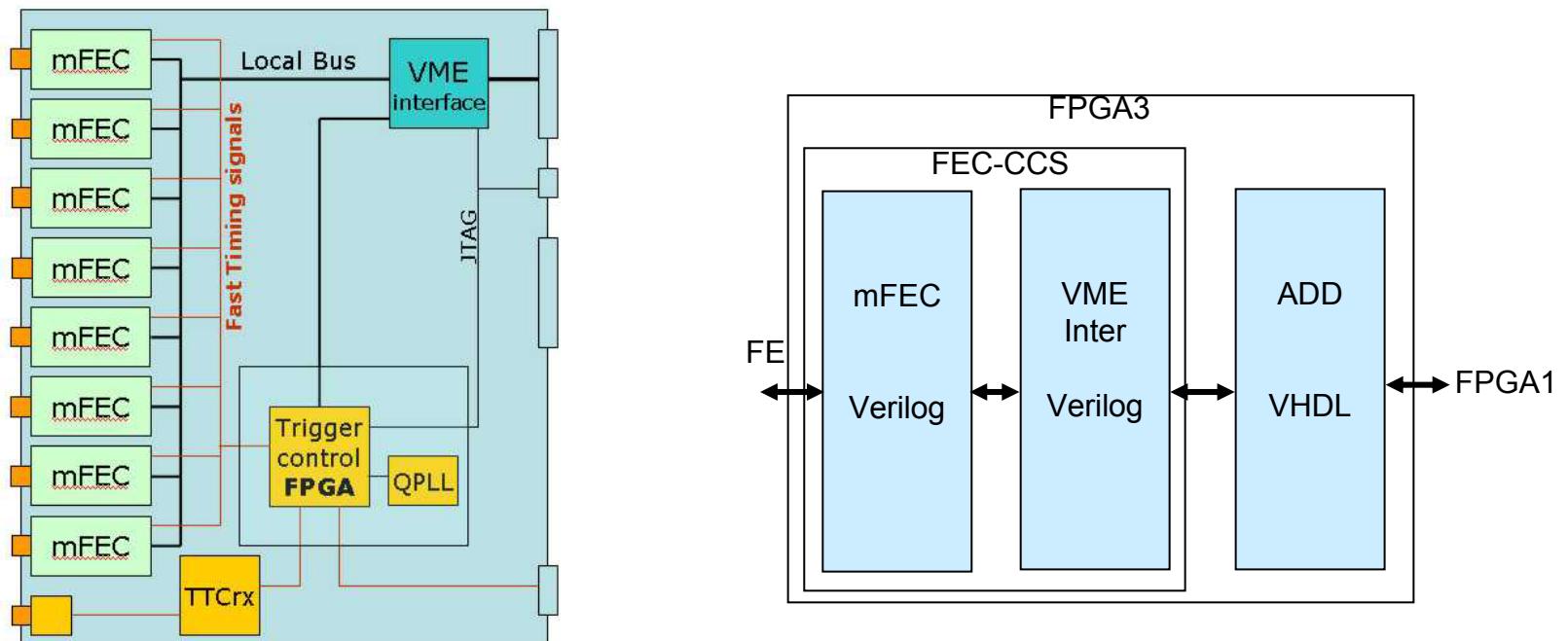


Digital design



FPGA3: FE Configuration

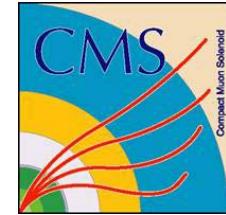
Re-use of block from CCS system



Additional edge removal functionality



FE Cards Tests



Production test:

Goals:

Checking crucial connections

Operate board at 40 MHz

Time Budget:

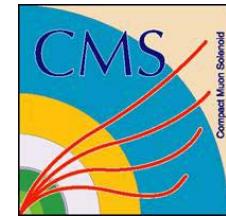
~2 minutes

Typical test cycle:

- (-1 boundary scan check) Option
- 1 I²C test (check presence of FENIX)
- 1 set of data loading in the DATA DPRAMs and 100 triggers in the RT DPRAM.
- 1 set-up of the FE card using the slow control
- 1 stimulus sending and data recording



Test Patterns and Simulation



Suitable test patterns:

- Re-use of the FENIX simulation test vectors
- Appropriate replica of a VFE data flow

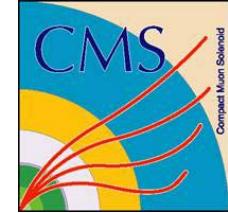
FAT: A simulation tool

- Copy of the real life environment of the FE card
- Any VFE data flow can be reproduced
- Slow Control logic identical to real life system

- ⇒ Useful to understand potential unexpected behaviour
- ⇒ Can be used to investigate problems during runs



Conclusion



- **FAT:** Flexible system reproducing real life environment of FE cards
- **Multiple applications:**
 - Production tests
 - Simulations
 - Radiation tests (backup)
- **Status:**
 - First system debugging run
 - First production run to start in November



Thank You For Your Attention



Questions?